

## DATA SHEET

Date 17-May-2017

customer name				Description	<b>CY1Y-2N2</b>			Quantity	<b>PCS</b>			
customer lot no.				Material lot no.				Temperature	<b>25°C</b>			
Project Lot no.				Sampling Standard	<b>MIL-STD-105E , normal inspection inspection level</b>							
Allow acceptable quality level		<b>Critical Defect AC=0 , RE=1 ; Major Defect: AQL=0.4 ; Minor Defect: AQL=0.65</b>										
Sampling Qty		<b>PCS</b>		Acceptable Qty	Minor Defect	Major Defect	Critical Defect	Disqualified Qty	Minor Defect	Major Defect	Critical Defect	
					<b>0 PCS</b>	<b>0 PCS</b>	<b>0 PCS</b>		<b>1 PCS</b>	<b>1 PCS</b>	<b>1 PCS</b>	
Project	Capacitance	Dissipation Factor	Insulation Resistance	Voltage Proof	Pitch	diameter of leader wire	diameter for the chip	Thickness	length of the lead wire	Sol	Appearance	
	<b>( C )</b>	<b>( D.F )</b>	<b>( I.R )</b>	<b>( T.V )</b>	<b>( P )</b>	<b>( d )</b>	<b>( D )</b>	<b>( T )</b>	<b>( L.L )</b>			
Standard Value	PF	1760	1.00	10GΩ	4000V	9.5mm	0.58mm	8.8mm	5.0	20.0		
		2640	Maximum	Minimum	AC	±1.5mm	±10%	Maximum	Maximum	Minimum		
NO.		<b>Product Shape:</b>							logo printing :			
Remark	1.ref. to the Capacitance ( c ) ,Dissipation Factor ( D.F ) ,Instrumentation:TH2617A, 1KHZ (Rate), 1.0V ( Voltage Testing ) 2. Instrumentation for Insulation Redittance:TH2683 3. Instrumentation for Voltage Proof : CS2671A 4. Dimensional inspection measuring tool for Appearance : Vernier caliper ( 0.02mm )											
Adjudged	<b>*Qualified</b>		<b>Disqualified</b>			Inspector	<b>Li Shuipeng</b>		Supervisor	<b>Zheng Xiuwen</b>		